

|                                   |                                       |  |             |
|-----------------------------------|---------------------------------------|--|-------------|
| <b>Notice of References Cited</b> | Application/Control No.<br>10/774,315 | Applicant(s)/Patent Under<br>Reexamination<br>HAO ET AL. |             |
|                                   | Examiner<br>Jin-Cheng Wang            | Art Unit<br>2628   | Page 1 of 2 |

#### U.S. PATENT DOCUMENTS

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name            | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-5,893,090                                     | 04-1999         | Friedman et al. | 707/3          |
| * | B | US-5,929,863                                     | 07-1999         | Tabei et al.    | 345/440        |
| * | C | US-6,400,366                                     | 06-2002         | Davies et al.   | 345/440        |
| * | D | US-5,801,688                                     | 09-1998         | Mead et al.     | 715/700        |
|   | E | US-  |                 |                 |                |
|   | F | US-  |                 |                 |                |
|   | G | US-  |                 |                 |                |
|   | H | US-  |                 |                 |                |
|   | I | US-  |                 |                 |                |
|   | J | US-  |                 |                 |                |
|   | K | US-  |                 |                 |                |
|   | L | US-  |                 |                 |                |
|   | M | US-  |                 |                 |                |

#### FOREIGN PATENT DOCUMENTS

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
|   | O |  |                 |         |      |                |
|   | P |  |                 |         |      |                |
|   | Q |  |                 |         |      |                |
|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

#### NON-PATENT DOCUMENTS

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)   |
|---|---|---|
|   | U | D. Keim, M. C. Hao, J. Ladisch, M. Hsu, U. Dayal, "Pixel Bar Charts: A New Technique for Visualizing Large Multi-Attribute Data Sets without Aggregation", HP Technical Report, April 11, 2001, pp. 1-10.                                       |
|   | V | M. Ankerst, M. Ester, H.-P. Kriegel, "Towards an effective cooperation of the computer and the user for classification", Proc. 6th Int. Conf. On Knowledge Discovery and Data Mining, (KDD '2000), Aug. 20-23, 2000, Boston, MA, 2000, pp. 1-10 |
|   | W | M.C. Hao, J. Ladisch, U. Dayal, M. Hsu, A. Krug; "Visual Mining of E-customer Behavior Using Pixel Bar Charts", HP Technical Report, June 20, 2001, pp. 1-7   |
|   | X | B. Shneiderman, "Tree Visualization with Treemaps: a 2-D Space-Filling Approach", ACM Transactions on Graphics, vol. 11, no. 1, pp. 92-99.  |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

|                                   |                                       |  |             |
|-----------------------------------|---------------------------------------|--|-------------|
| <b>Notice of References Cited</b> | Application/Control No.<br>10/774,315 | Applicant(s)/Patent Under<br>Reexamination<br>HAO ET AL. |             |
|                                   | Examiner<br>Jin-Cheng Wang            | Art Unit<br>2628   | Page 2 of 2 |

**U.S. PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Name | Classification |
|---|---|--|-----------------|------|----------------|
|   | A | US-  |                 |      |                |
|   | B | US-  |                 |      |                |
|   | C | US-  |                 |      |                |
|   | D | US-  |                 |      |                |
|   | E | US-  |                 |      |                |
|   | F | US-  |                 |      |                |
|   | G | US-  |                 |      |                |
|   | H | US-  |                 |      |                |
|   | I | US-  |                 |      |                |
|   | J | US-  |                 |      |                |
|   | K | US-  |                 |      |                |
|   | L | US-  |                 |      |                |
|   | M | US-  |                 |      |                |

**FOREIGN PATENT DOCUMENTS**

| * |   | Document Number<br>Country Code-Number-Kind Code | Date<br>MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
|   | N |  |                 |         |      |                |
|   | O |  |                 |         |      |                |
|   | P |  |                 |         |      |                |
|   | Q |  |                 |         |      |                |
|   | R |  |                 |         |      |                |
|   | S |  |                 |         |      |                |
|   | T |  |                 |         |      |                |

**NON-PATENT DOCUMENTS**

| * |   | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)  |
|---|---|--|
| ✓ | U | D. Keim, M.C. Hao; U. Dayal; "Hierarchical pixel bar charts", IEEE Trans. On Visualization and Computer Graphics, Vol. 8, No. 3, July-Sept. 2002, pp. 255 – 269. |
|   | V |  |
|   | W |  |
|   | X |  |

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.